



Universität Hamburg

DER FORSCHUNG | DER LEHRE | DER BILDUNG



CMS Phase 1 Pixel Upgrade

LEXI Cluster Meeting

DESY, Hamburg, DE

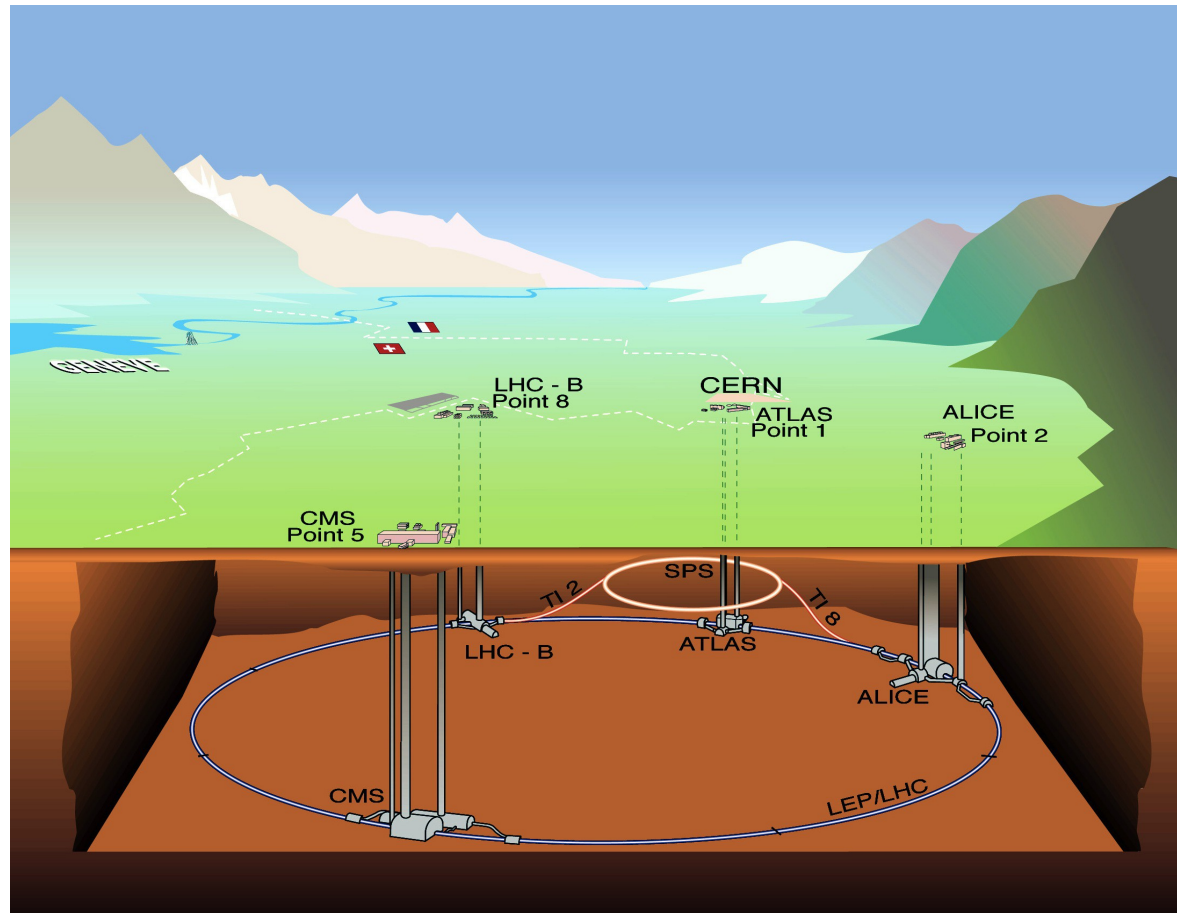
11-12 October, 2012

Jennifer Sibille

University of Hamburg

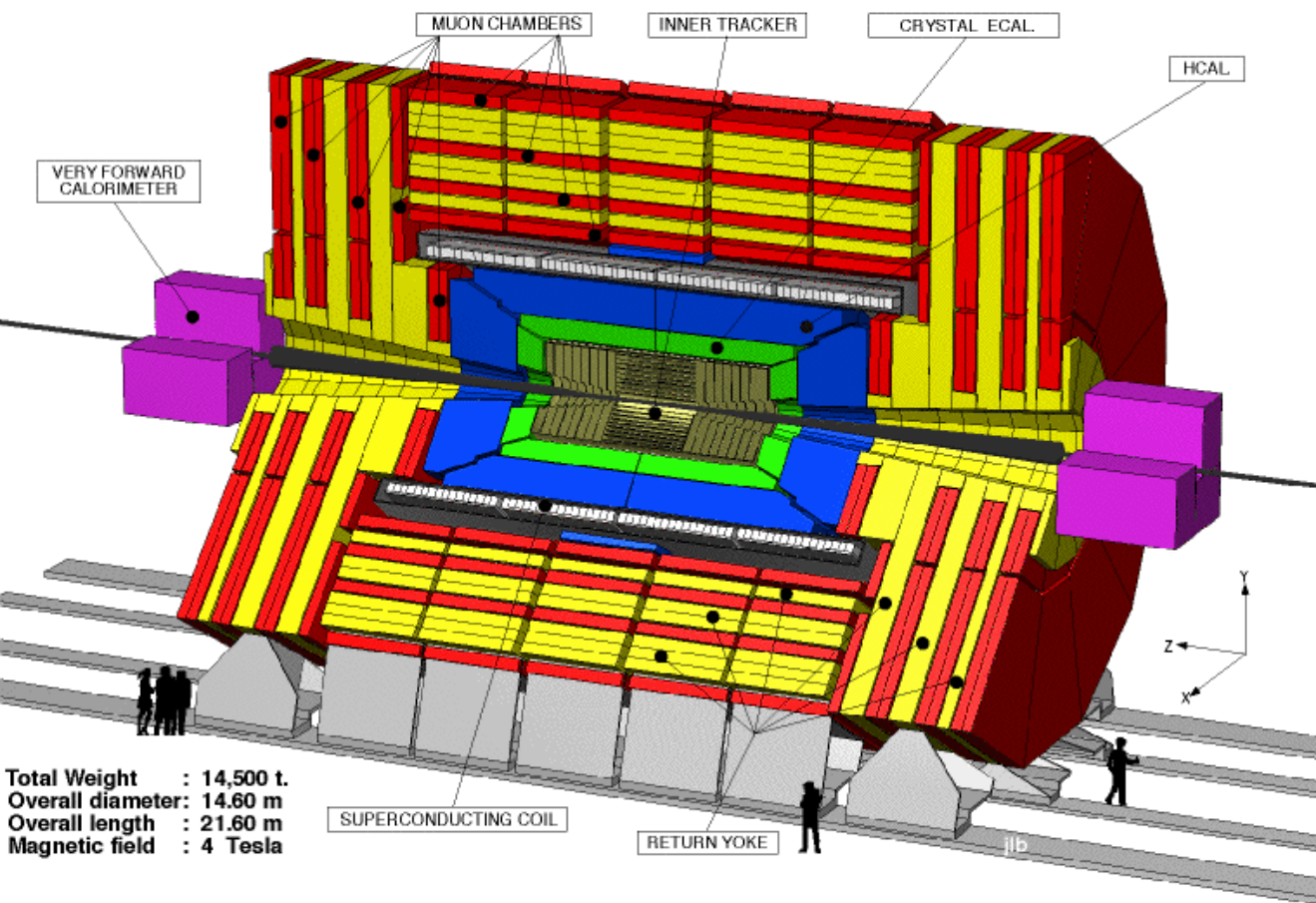
- Introduction
- Motivation for the upgrade
- The upgraded pixel detector
- Contributions of DESY/UHH
- Summary and Outlook

The Large Hadron Collider



- Located at European Center for Nuclear Research (CERN) along French-Swiss border
- pp collider with design center-of-mass energy of 14 TeV (currently 8 TeV), 27 km circumference

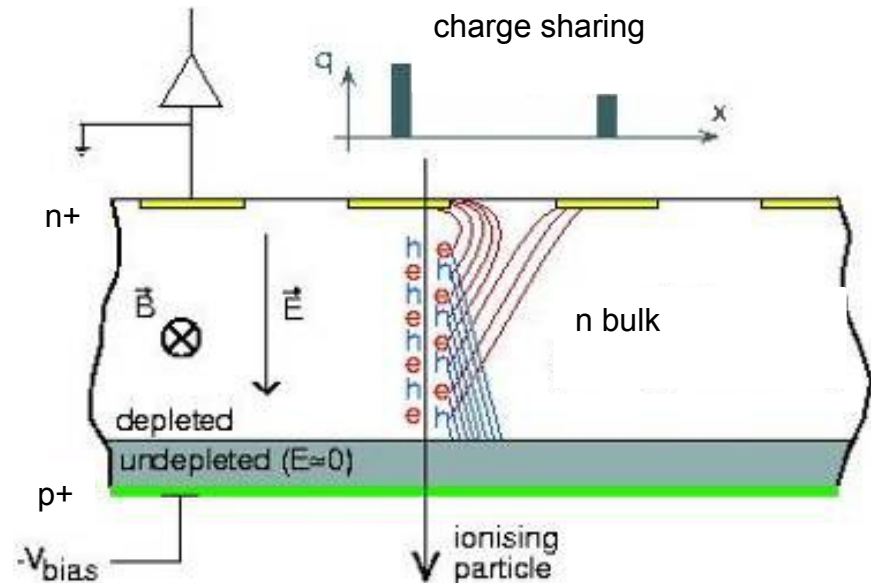
The CMS Detector



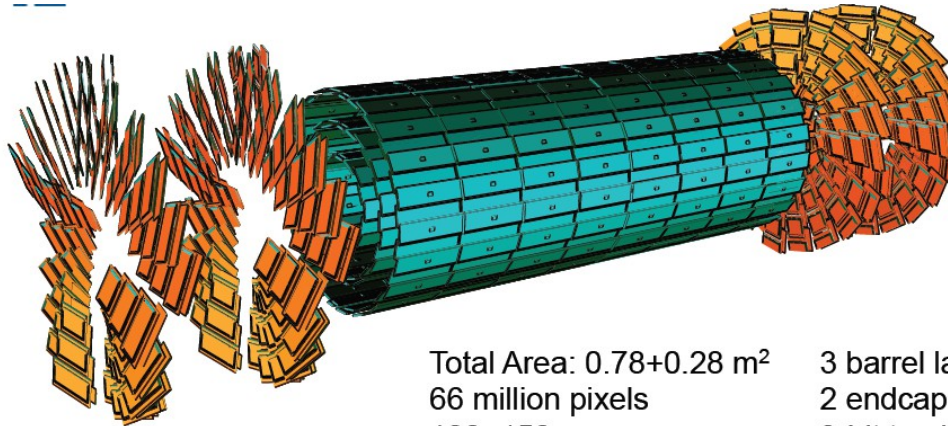
- 3.8 T solenoid magnet
- Silicon tracker
 - Strips ~9 million ch.
 - Pixels ~66 million ch.
- Electronic calorimeter
 - PbWO_4 crystals
- Hadronic calorimeter
 - Brass/scintillator
- Muon chambers embedded in return yoke

Operating Principle of a Silicon Pixel Detector

- Charged particle passes through silicon, creates electron/hole pairs
- Electric field in sensor causes electrons/holes to separate
 - Electrons are collected at pixel implant
- Magnetic field: charges experience Lorentz force
 - Charge shared between multiple pixels
- Charge sharing leads to better spatial resolution ($\sim 10 \mu\text{m}$)

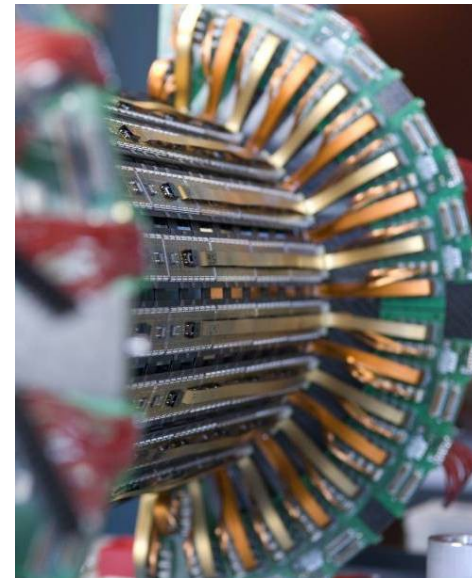
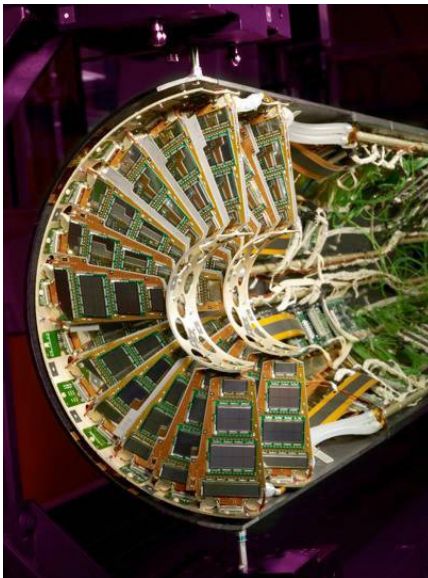


The Present Pixel Detector



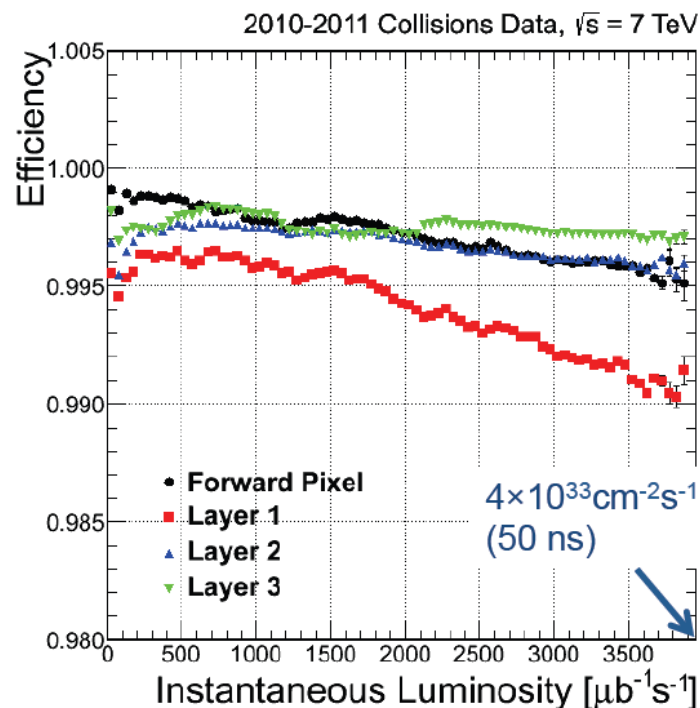
Total Area: $0.78+0.28 \text{ m}^2$
66 million pixels
 $100 \times 150 \text{ }\mu\text{m}$

3 barrel layers @ 4,7,11 cm
2 endcap disks
3-hit tracking $|\eta| < 2.5$



Motivation for the Upgrade

- Dead time of readout chip (ROC)
 - Can already clearly see drop in efficiency as a function of instantaneous luminosity
- Radiation damage in sensors leads to less charge sharing (smaller Lorentz angle)
 - Degradation of spatial resolution
- Replace entire pixel detector during extended year end technical stop in 2016/17!

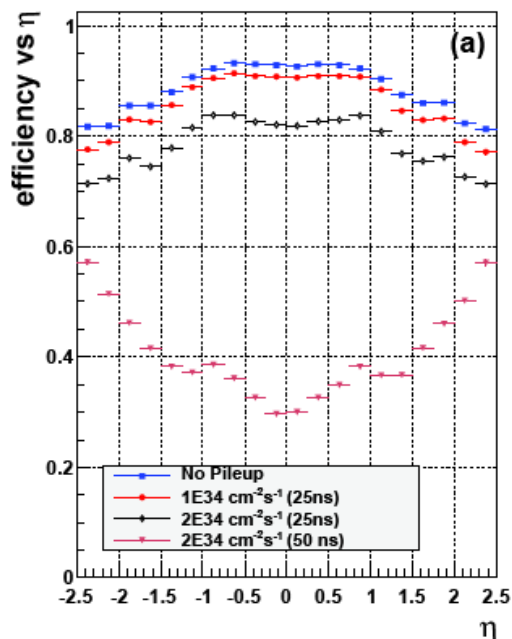


CMS Pixel Detector Upgrade TDR

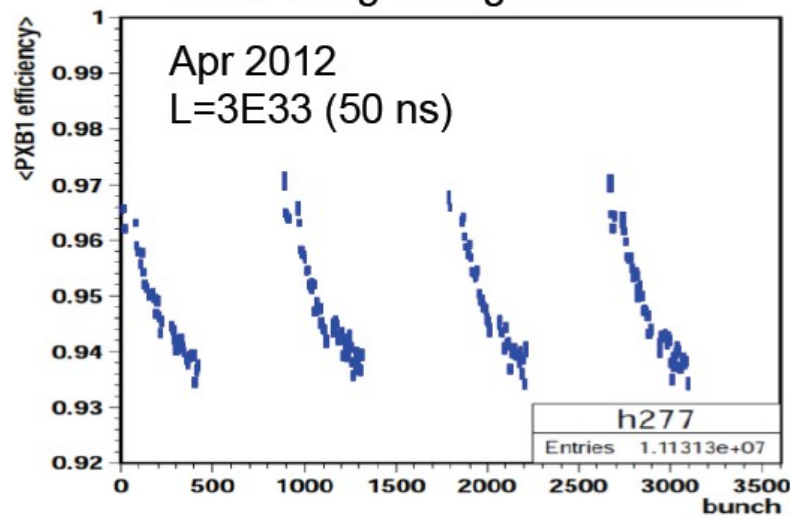
A More Dramatic View...

- Note: L1 rate already beyond design expectation!
 - $0.6\text{E}34 = 30 \text{ PU @ } 50 \text{ ns}$ equivalent to $1.2\text{E}34 @ 25 \text{ ns}$
- Expectation at $2\text{E}34 @ 25 \text{ ns}$: **16% data loss** at layer 1!

Efficiency vs. η in simulated $t\bar{t}$ events



Barrel Layer 1
 ROC Dynamic Inefficiency
 Buffer filling during bunch trains



Data Loss Mechanisms: Current Chip

Pixel busy:

0.09% / 0.18% / 0.48%

Double column busy:

0.003% / 0.18% / 1.3%

total data loss @ 100kHz L1A:

1.3% @ 11cm

2.7% @ 7cm

16% @ 4cm

Data Buffer full:

0.09% / 0.17% / 0.83%

Timestamp Buffer full:

0 / 0.05% / 6.8%

Readout and double column reset:

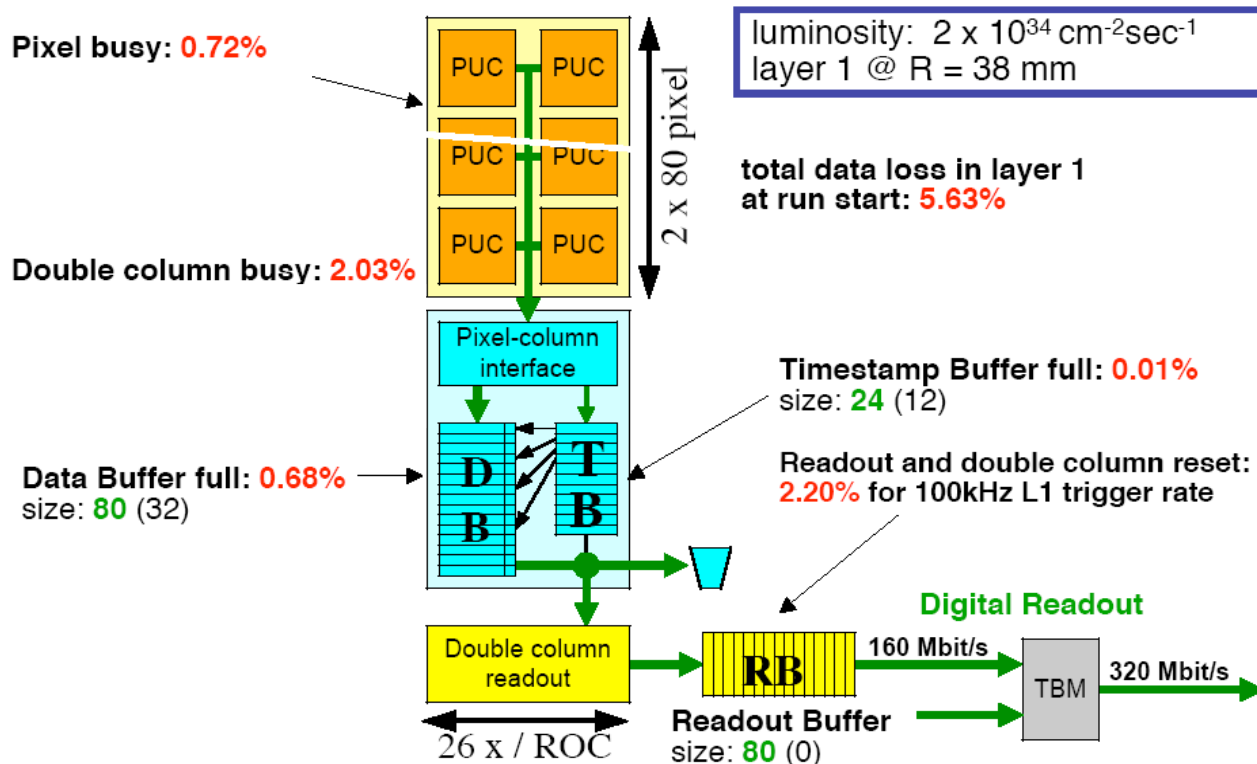
1.1% / 2.1% / 6.7%

for 100kHz L1 trigger rate

Main sources
of data loss

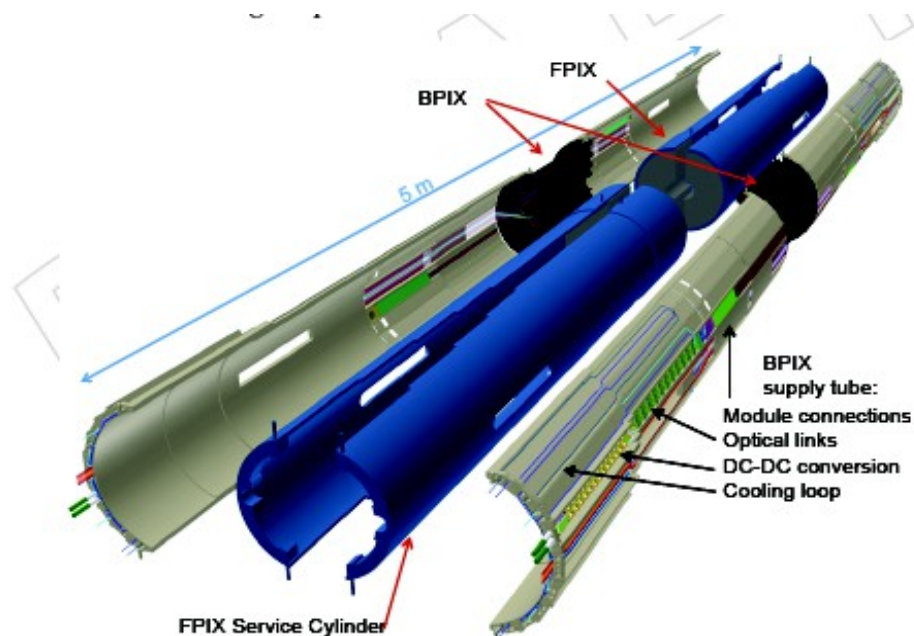
Present psi46 readout chip (ROC) simulated at 2x LHC design luminosity

Data Loss Mechanisms: New Chip

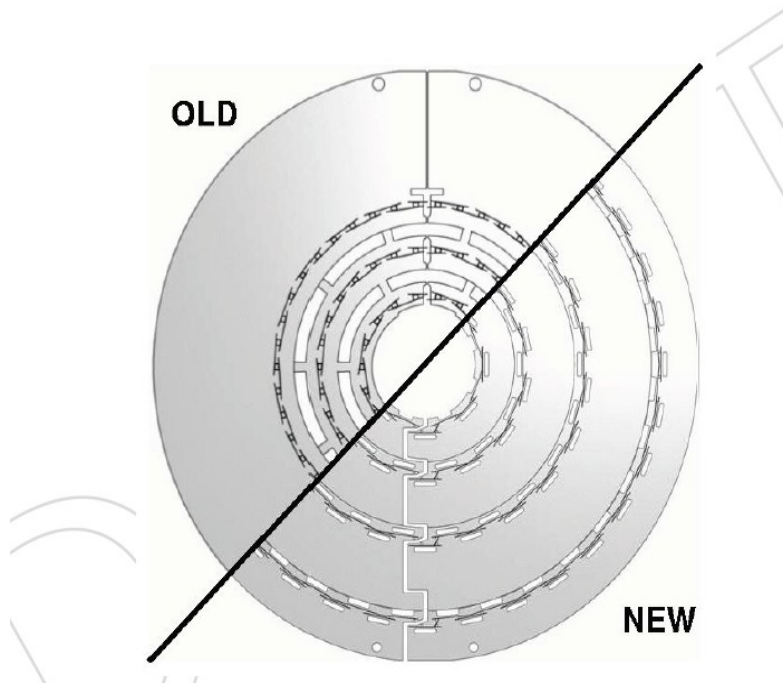


- Increased timestamp and data buffers
- Added readout buffer
- Digital readout

The Upgraded Pixel Detector

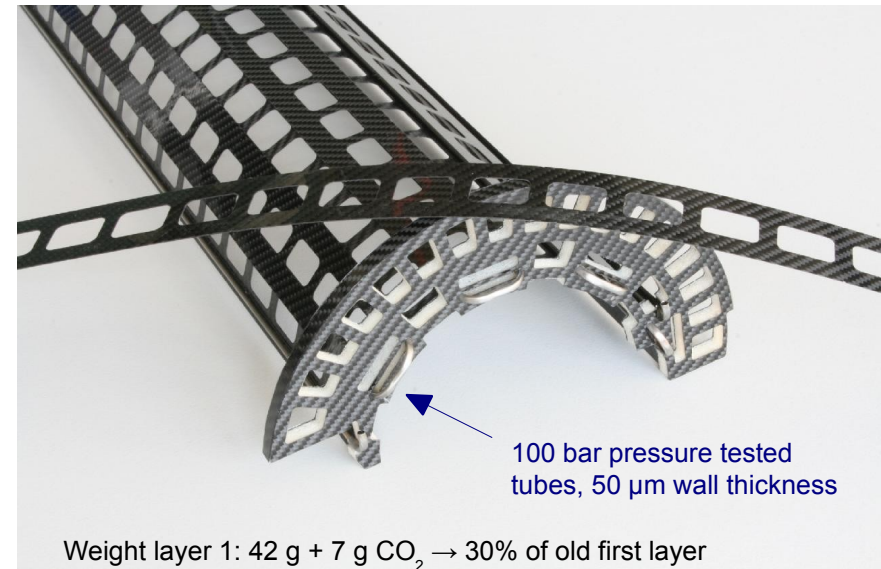


- 4 layer + 3 disk layout, reduced inner radius
- Low mass mechanics and service cylinders, move material out of active region
- New digital ROC, based on present psi46
- Optical readout: analog 40 MHz → digital 320 Mbit/s (x2)
- Powering with dc-dc converters, using existing cables
- Dual-phase CO₂ cooling, low mass/low temperature
- Current detector uses C₆F₁₄
- Has been operating at ~17 C (2010-2011) and ~10 C (2012), want to go to ~-10 C



2 identical half-shells with 1184 modules (79M pixels)

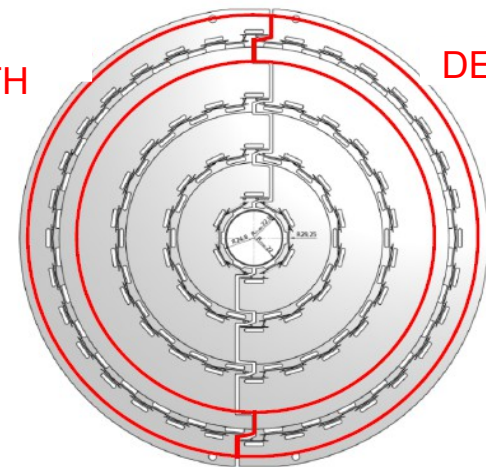
Layer	Radius (mm)	# modules	Group
1	29	96	CH (PSI)
2	68	224	CH (PSI)
3	109	352	CERN, IT, TW, FI
4	160	512	DE

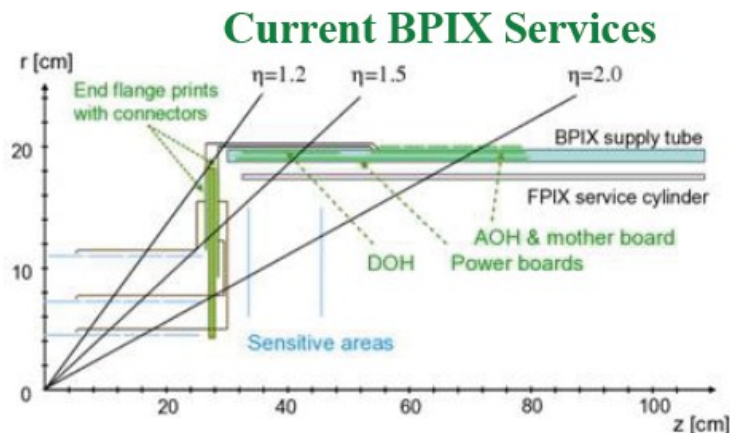


X/X_0

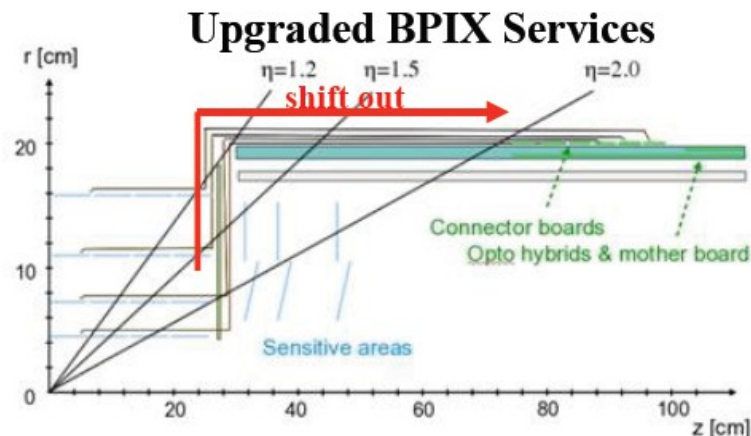
KIT + RWTH
Aachen

DESY + UHH



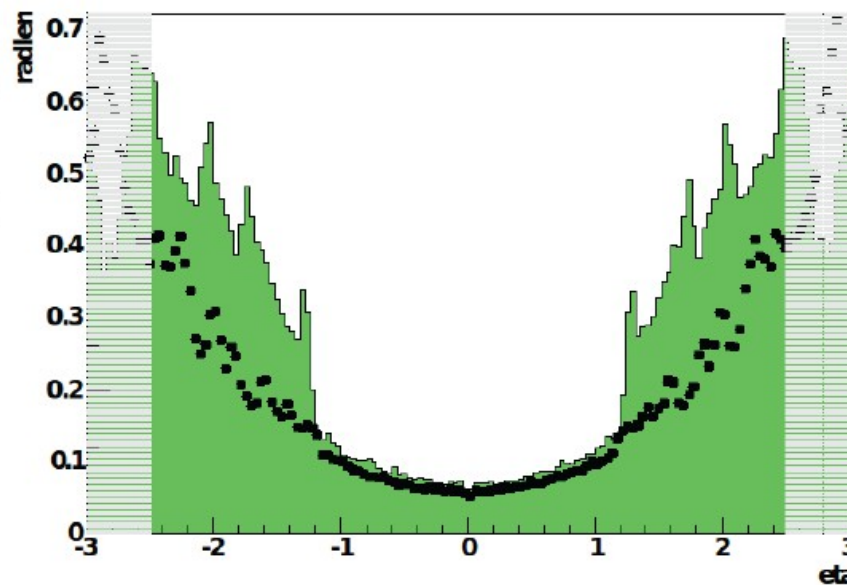


$\eta < 2.2$: weight = 16.9 Kg (3 layer)

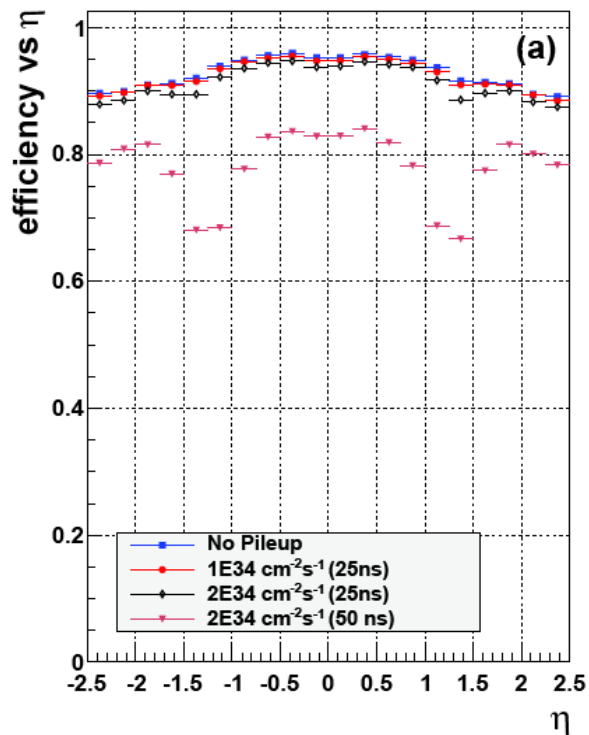


$\eta < 2.2$: weight = 6.5 Kg (4 layer)

- Move services to higher rapidities outside tracker acceptance
- Optimize cooling/support/material
- Possible to add 4th layer without increase in X_0
- Substantial improvement in forward region

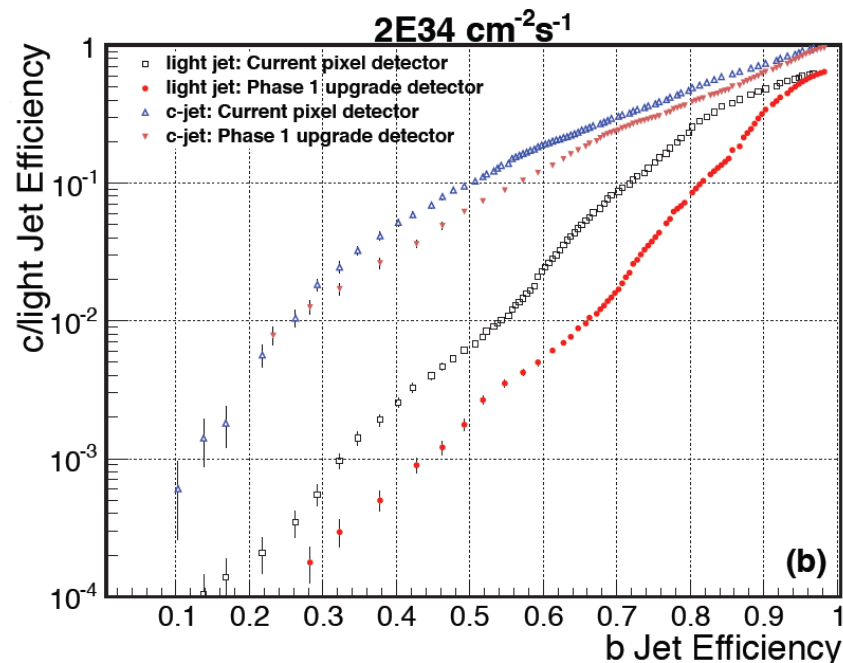


Performance of Upgraded Detector



Efficiency vs. η in simulated $t\bar{t}$ events

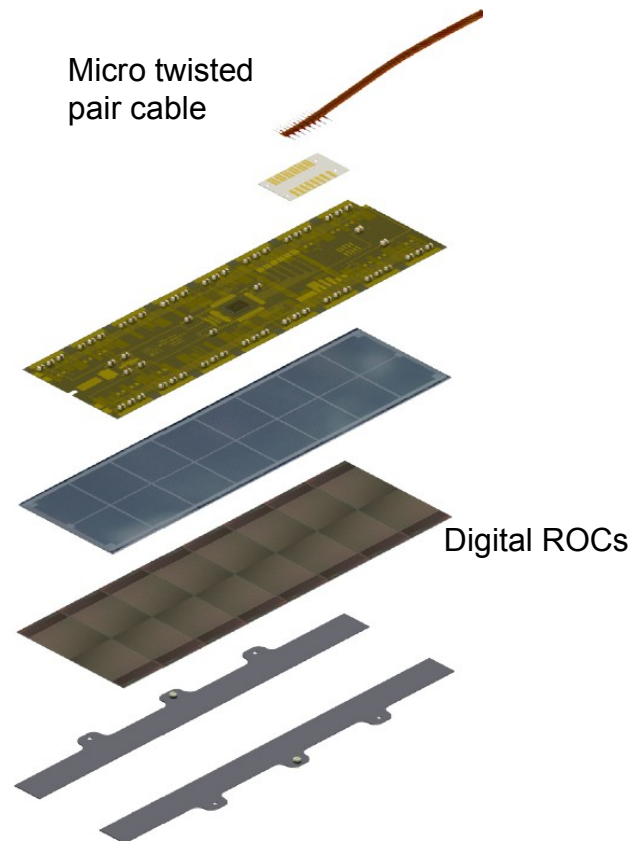
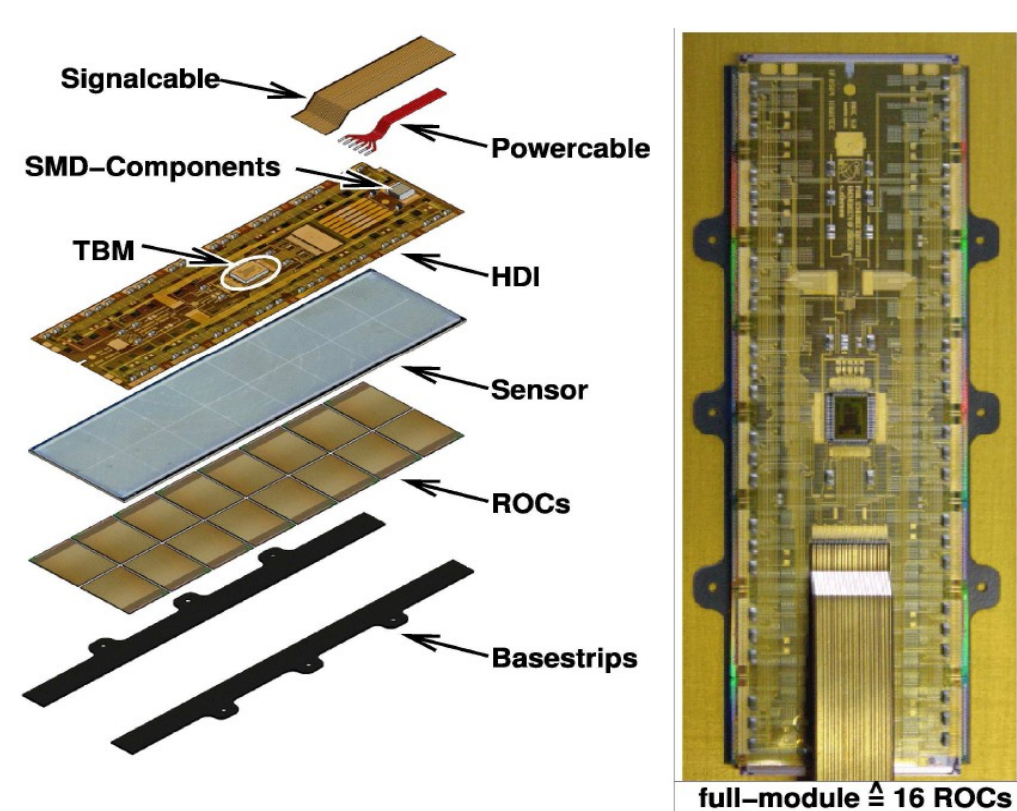
Reminder: 2E34 cm²s⁻¹ (25 ns) with current detector only at ~80% efficiency!



- Combined secondary vertex b -tagger
- Factor 2-4 better rejection of light quark jets (without further retuning of the algorithm!)

CMS Pixel Detector Upgrade TDR

Module Building

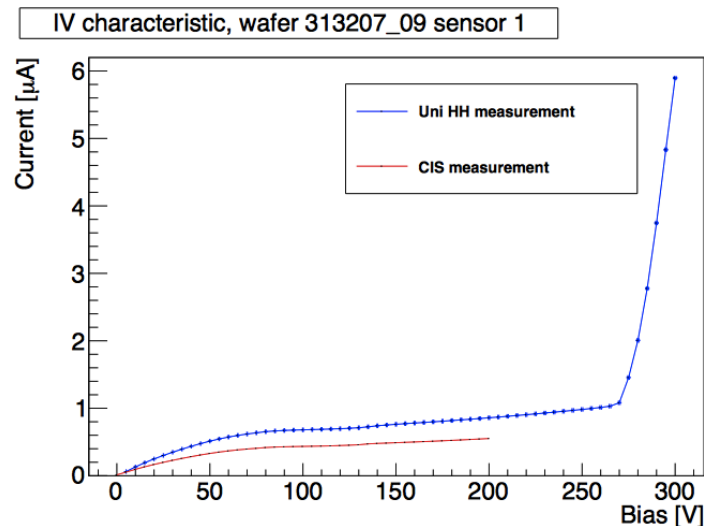
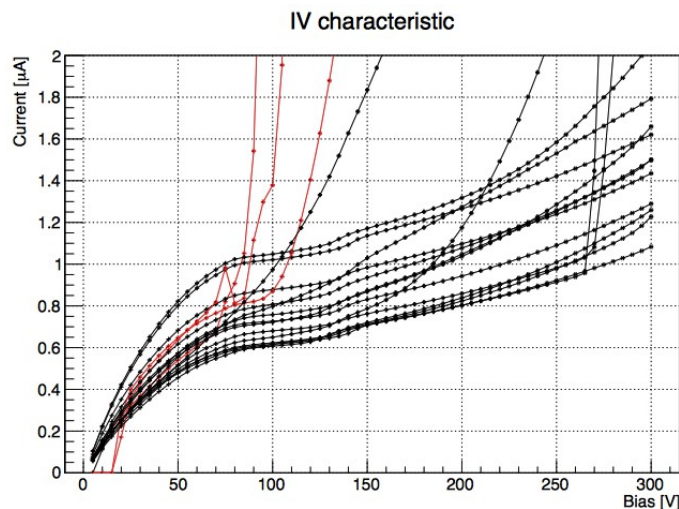
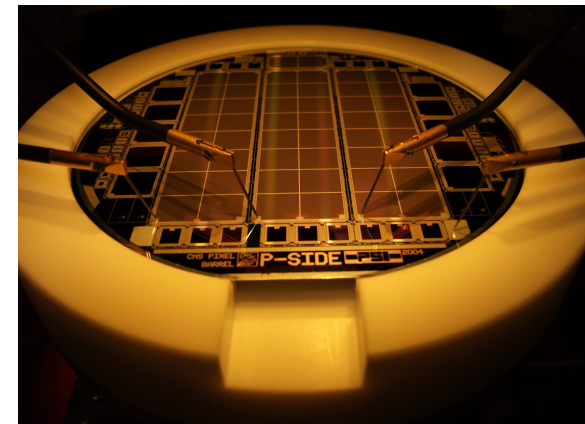


- Production of 4th layer split into two halves
- DESY + UniHH
- KIT + RWTH Aachen

- Throughput limited by bump deposition
- 2 modules/day (350 modules/site)
→ 175 days!

Wafer IV Measurements (UHH)

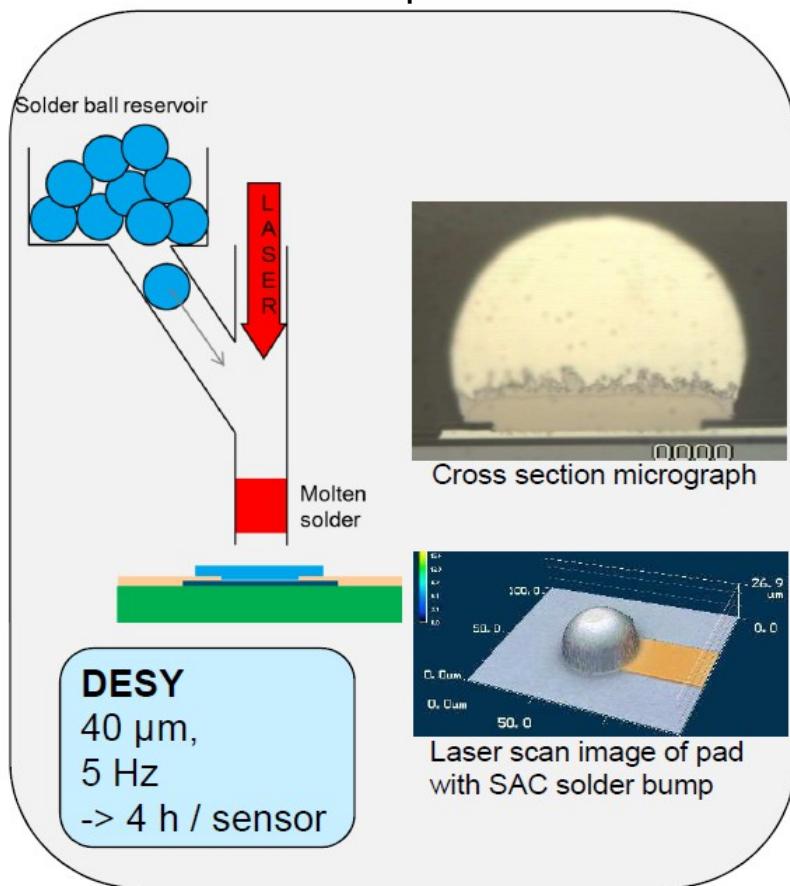
- Measure IV curves of sensors on-wafer to check quality before bump bonding
- Scratches, etc. show up in early breakdown
- Measured first batch of sensors, measurements agree well with the data and measurements provided by manufacturer (CiS Erfurt)
- After under bump metalization and dicing, will measure IV curves again



Difference consistent with difference in temperature

1. Bump Deposition

Pac Tech SB² Jet
66560 bumps/module



2. Flip-chip bonding

FEMTO flip-chip bonder from Finetech

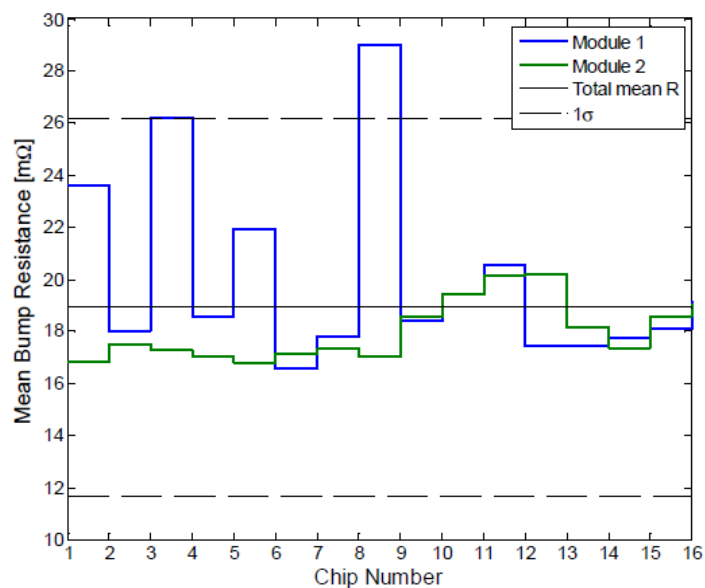
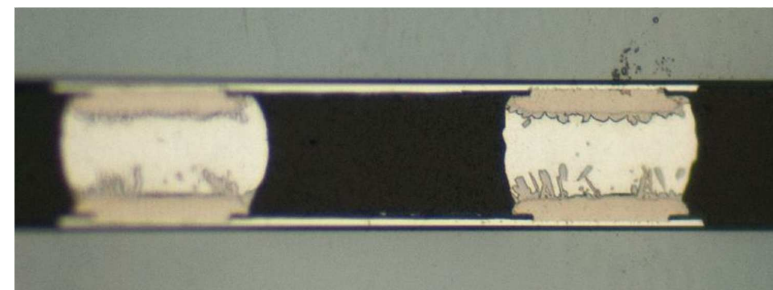
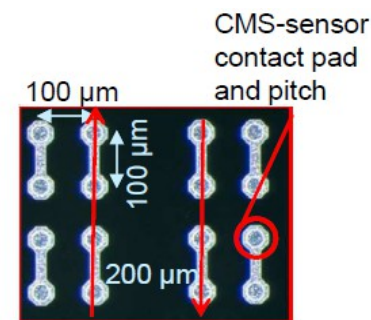
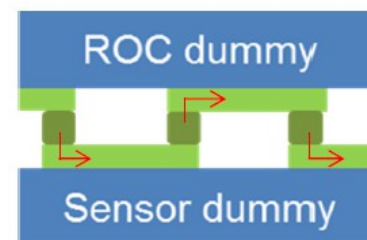
- Accuracy < 1 μm
- KGD probing before bonding
- ~ 1 min./chip (without probing)
- Reflow ~ 3 min.



Jan Hampe, Phase 1 Pixel Upgrade Workshop, 28.08.2012

Module Building: Bump Bonding (DESY)

- 26 double columns/ROC, connected in daisy chain
- Resistance measurement
 - Single dead pixel $\rightarrow$ open circuit

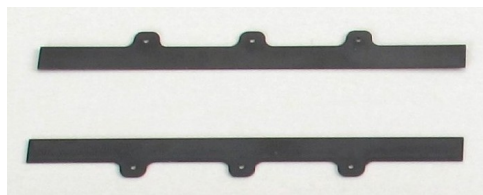
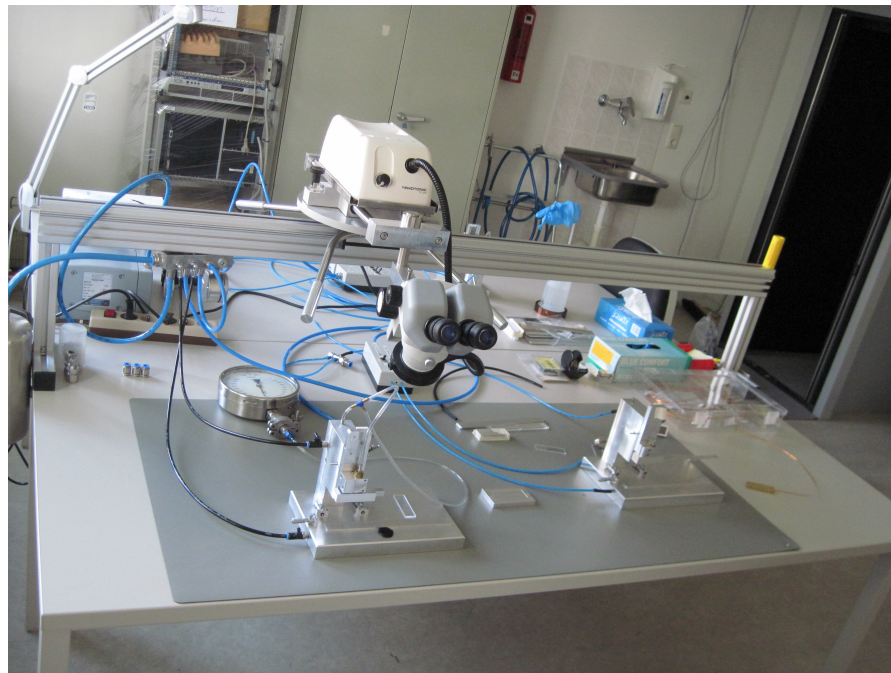


First 8 chips of module 1 used several times to adjust bonding parameters!

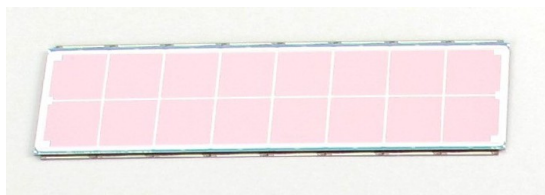
Jan Hampe, Phase 1 Pixel Upgrade Workshop, 28.08.2012

Module Building: Gluing (UniHH)

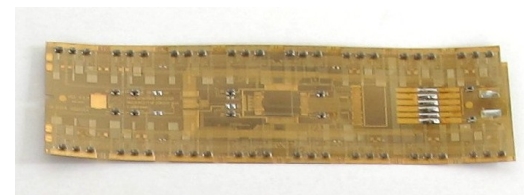
- Custom made tools, need some modifications from the ones used to build current detector
 - ROC slightly larger (increased buffers)
- Several gluing steps
 - Base strips to bare module
 - HDI to module
 - Cable to HDI/module
 - Curing takes 6 hours for each step



Base Strips



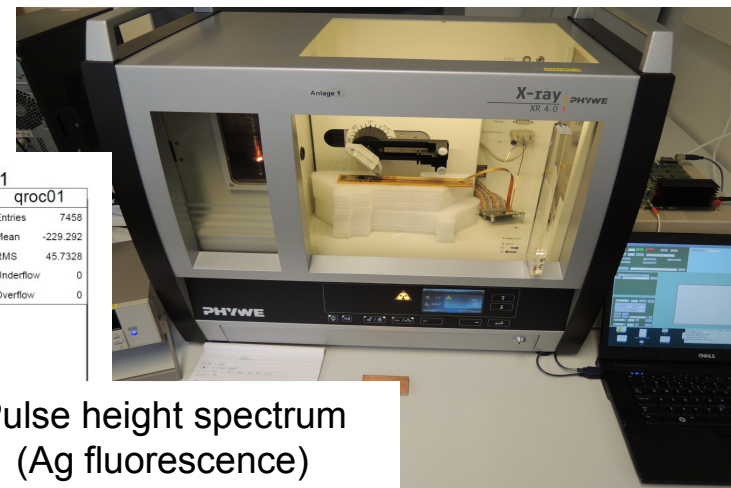
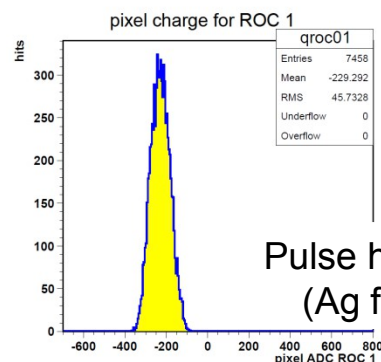
Bare Module



HDI

Module Calibration

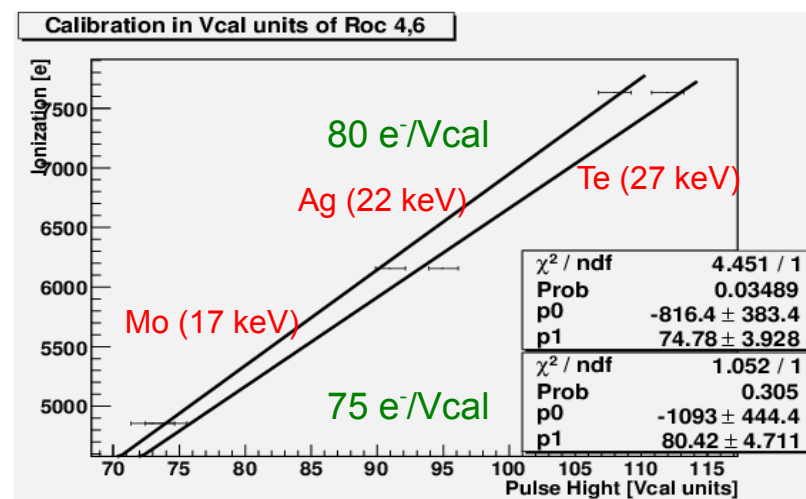
- Pixels have a threshold for sparsified readout
- The pixel thresholds are adjusted per pixel to obtain a uniform response using internal calibration pulses
- Absolute energy calibration using Xray source ($K\alpha$ lines)



Pulse height spectrum
(Ag fluorescence)

• Having the x-ray setups at each site means we can do many other studies, i.e.:

- compare old and new modules
- temperature dependence of energy calibration



Timeline (Preliminary!)

2012

- Setup infrastructure for bump bonding, module assembly testing
 - Establish bump bonding technology on existing module

2013

- Order sensors
- Prepare for series production
 - Spring: All production centers must be approved by CMS

2014/15

- Series production

2016

- Assemble 4th layer @DESY
- Group test
- Transport to Switzerland
- Installation in CMS at extended year end stop 2016/17



Phase 1 Pixel Upgrade:

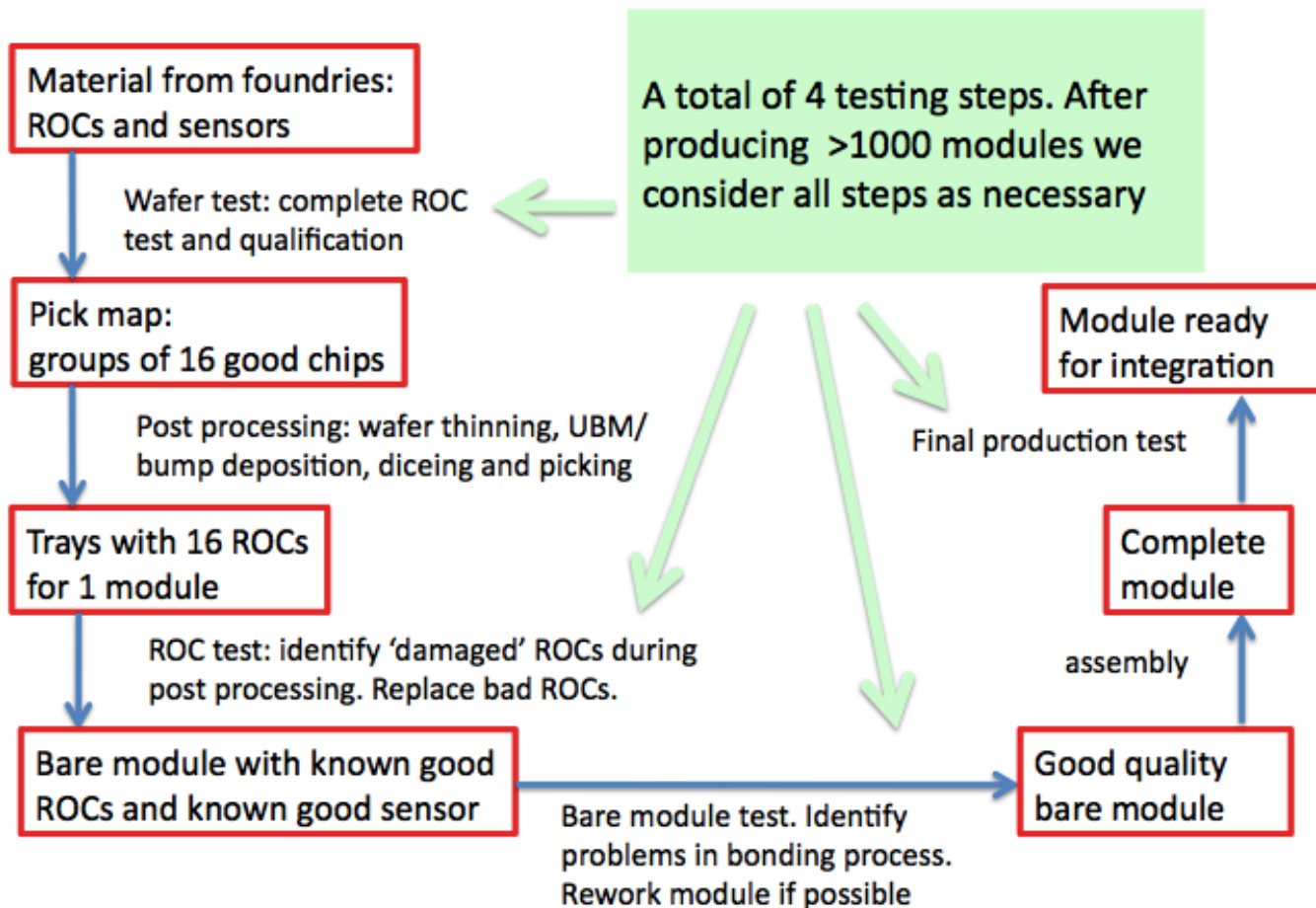
- Integrated luminosity (radiation damage) → degraded spatial resolution
- Increased instantaneous luminosity → severe dead time in present pixel chip
 - **Need new pixel detector!**
- Upgrading from 3 → 4 layers and improving material budget → better physics performance
 - i.e. *b*-tagging: Light quark rejection improves by at least factor 2-4
- New digital readout chip greatly reduces dead time/data loss
- Installation in 2016/17 extended year end shutdown

DESY/UHH:

- DESY + UHH will build half of the 4th layer (other half by KIT + RWTH Aachen)
- Many different construction and testing setups needed
 - wafer IV-tests
 - module testing
 - bump bonding
 - x-ray calibration
 - module gluing
 - testbeams
- Setups for all these tasks exist or are in progress, but still a lot of work to do!

Backup Slides

Work flow



Chip test on flip chip bonder

ROC test after post processing → individual (picked) ROCs

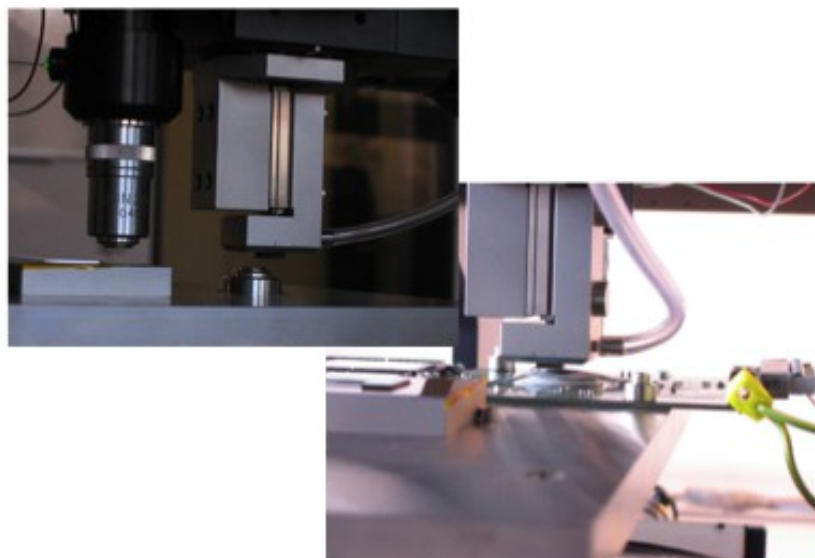
Painful from handling point of view

At PSI done on flip chip bonder. Chip on tool at well measured position anyway

Mandatory step: Chip failure on 1% level → 15 % level for module

Only quick functional test:

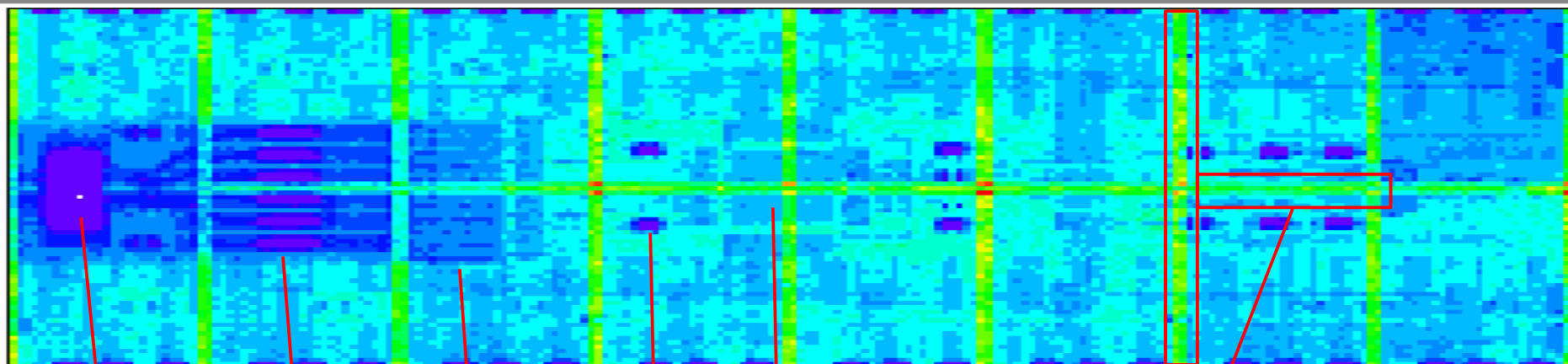
- Measure current consumption before/after initialization
- Check I2C interface
- Check token
- Set analog current
- read temp DAC
- Measure LVDS levels
- Measure analog levels
- Pixel alive test



Bare module test

- Routinely made for all bare modules (time needed: ~15 minutes)
- **Very fast feedback to bumping / bonding process** (same day in our case)
 - Processes are never stable. Don't expect that once you made it through the learning curve, you will only produce good bare modules.
 - A quick feedback will save you a lot of money.
 - Ideally this should be done at the bump bond vendors place
- Last stage where module can be reworked.
 - Components to finish module (HDI, signal cables, base strips) are substantial contribution to budget
 - Rework can be done successfully (PSI: ~80% success for selected modules, IZM did it routinely for ATLAS modules, efficiency unknown to me)
- Tests done:
 - Sensor IV curve
 - ROC current consumption before/after initialization
 - I2C test
 - Token passage
 - Set analog current
 - Scan through all DACs
 - Analog level measurement
 - **Bump yield test**

X ray map through the HDI



Bias
filter
cap.

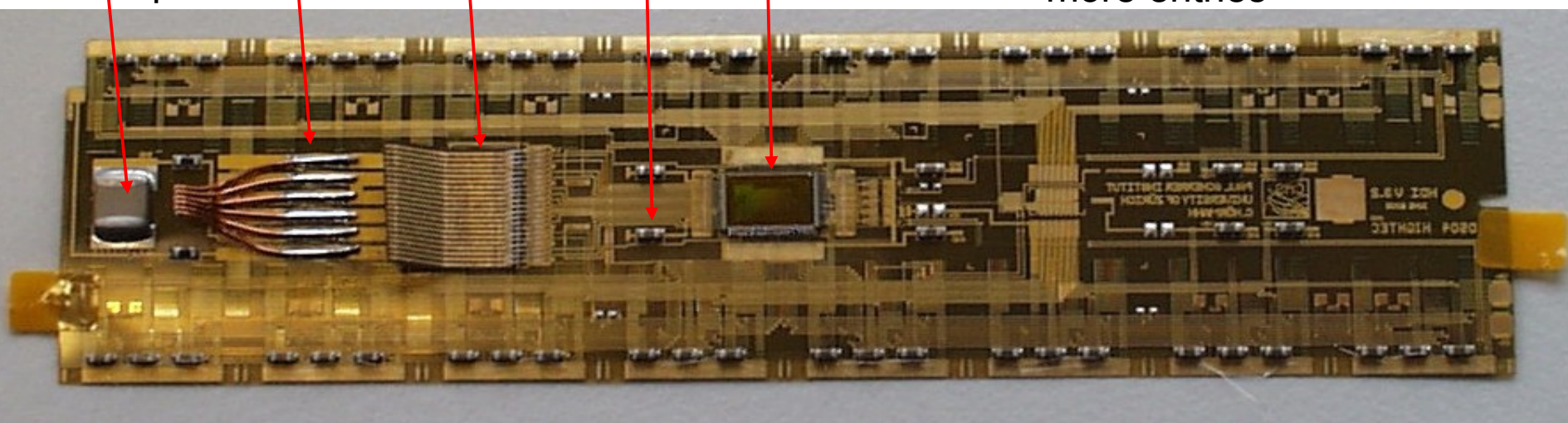
Power
cable

Signal
cable

SMD
comp.

TBM

Edge pixels are bigger
→ more entries



Transverse Impact parameter: Muons, 50 pileup

